4th International Conference on Technology and Social Science (ICTSS 2020)

Keynote Lecture 03 Abstract

> Challenges of Analog and Mixed-Signal IC Testing Technologies in Digital Explosion Era

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5W 1H of

Analog and Mixed-Signal IC Testing Technologies

1 What, 2 Why, 3 Who, 4 Where, 5 When 1 How

1st W: What is analog IC testing ?

LSI test and measurement are different

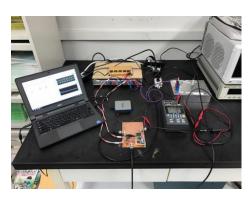
- Production Test :
 - Decision of "Go" or "No Go"

Today's focus

LSI testing \rightarrow manufacturing engineering.

Measurement / Characterization

Accurate performance evaluation of circuit





2nd W: Why analog IC testing now ? Hot Applications in IC Industry Automotive application ppm (parts per million) \rightarrow ppb (parts per billion) low quality \rightarrow out of business IoT systems A lot of sensors, interface analog circuits

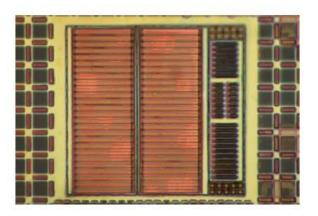
High reliability, Low cost system



High quality, low cost testing of analog IC is important !

3rd W: Who are involved ?

- Semiconductor IC companies
- Automatic IC test equipment manufactures
- Analog IC testing research groups in universities



Analog IC developed with Gunma U. and ASO Corp.

4th W: Where is analog IC test research done ?

Kobayashi Lab at Division of Electronics and Informatics Gunma University , Japan

The largest research group in this area among Japanese universities

Research collaboration with semiconductor companies, Automatic IC test equipment manufactures

5th W: When ?

- Kobayashi group has been involved in this area more than 15 years
 - A lot of journal and international conference papers
 - Serve as committee member of prestigious conferences



ICテスト分野で最大の国際会議International Test Conference (ITC) は毎年秋に米 国で開催される (<u>ITC 2016記事の一覧ページ</u>)。そのアジア版である「ITC Asia」が創 設され、第1回として「ITC Asia 2017」(<u>ホームページ</u>)が2017年9月13日〜15日に台 湾・台北市の台北南港展覧館で開催された。

Today, it is a hot topic due to automotive and IoT system applications

1H: How ?

How Kobayashi lab has approached will be presented in details:



Invited Paper Session 2:

Analog/Power Supply Circuits and Their Related Technology

Room A Dec. 3 (Thur) 10:20-11:00

Haruo Kobayashi,

"Challenges of Analog and Mixed-Signal IC Testing Technologies in Digital Explosion Era".